## RECEIVED CENTRAL FAX CENTER JUL 0 7 2008

## LISTING OF CLAIMS:

1. (Original): A method of manufacturing liquid crystal display device comprising the steps of:

forming an organic material film having projections and depressions, using a photoembossing material, on an insulating film on an underlying electrode in a thin-film transistor of an active-matrix liquid crystal display device;

exposing said insulating film in a contact-hole-forming-area by reducing a thickness of said organic material film by a dry etching to said organic material film; and forming a contact hole by a dry etching to the exposed insulating film.

- 2. (Original): A method as claimed in claim 1, further comprising the steps of: exposing said underlying electrode in forming said contact hole; and contacting the exposed underlying electrode with a reflective electrode by forming said reflective electrode on the resulting structure.
- 3. (Original): A method as claimed in claim 1, wherein said photo-embossing material is a material patternable by an exposing step and a baking step.
- 4. (Original): A method as claimed in claim 3, wherein said organic material film is formed by exposing and baking said photo-embossing material in forming said organic material film.

+1-213-830-5741

p.3

- 5. (Original): A method as claimed in claim 4, wherein a halftone mask or a diffraction mask is used in exposing.
- 6. (Currently amended): A method as claimed in claim 1, wherein the dry processes are performed from the step of forming said organic material film to the step of forming said contact hole.
- 7. (Currently amended): A method as claimed in claims claim 1, wherein the step of exposing said insulating film and the step of forming said contact hole are performed in a single apparatus.
- 8. (Currently amended): A method as claimed in claim 1, wherein [[a]] the dry etching process in the step of exposing said insulating film is performed in an Inductively Coupled Plasma mode or a reactive ion etching mode.
- 9. (Original): A method as claimed in claim 1, wherein said liquid crystal display device is a reflective type of liquid crystal display device or a transflective type of liquid crystal display device.
- 10. (New): A method as in claim 1, wherein the projections and depressions of the organic material film are formed by subjecting the photo-embossing material to a mask and exposure to light, wherein the projections and depressions in the organic material film include a thinnest region corresponding to the contact-hole-forming-area.

Jul 07 2008 2:38PM LIU & LIU

+1-213-830-5741

p. 4

11. (New): A method as in claim 10, wherein the mask comprises a light shield portions corresponding to the projections, semi-transparent regions corresponding to the depressions, and a transparent portion corresponding to the thinnest region in the organic material film.

12. (New); A method as in claim 10, wherein the insulating film is exposed by dry etching the thinnest region of the organic material film.

13. (New): A method of manufacturing a liquid crystal display device comprising: forming a thin-film transistor on a substrate;

forming an insulating film over the thin-film transistor;

disposing an organic material film above the insulating film;

forming projections and depressions in the organic material film, including a thinnest region corresponding to a contact-hole-forming-area;

dry etching the thinnest region of the organic material film to expose a region of the insulating film; and

dry etching the exposed region of the insulating film to form a contact hole.

14. (New): The method as in claim 13, wherein the organic material film comprises a photo-embossing material, wherein the projections and depressions are formed by subjecting the photo-embossing material to a mask and exposure to light.

+1-213-830-5741

p.5

Jul 07 2008 2:39PM LIU & LIU

15. (New): The method as in claim 14, wherein the mask comprises a light shield

portions corresponding to the projections, semi-transparent regions corresponding to the

depressions, and a transparent portion corresponding to the thinnest region in the organic

material film.

16. (New): The method as in claim 13, further comprising the steps of forming an

electrode layer below the insulating layer, wherein a region of the electrode is exposed after the

contact hole is formed; and forming a reflective electrode above the projections and depressions

and the exposed region of the electrode layer, wherein the reflective electrode contacts the

exposed region of the electrode layer.

17. (New): The method as in claim 13, wherein only dry processes are performed from

forming said projections and depressions in the organic material film to forming said contact

hole.

18. (New): The method as in claim 13, wherein dry etching the thinnest region of the

organic material film and dry etching the exposed region of the insulating film are performed in a

single apparatus.

19. (New): The method as in claim 13, wherein dry etching to expose the insulating film

is performed in an inductively coupled plasma mode or a reactive ion etching mode.

20. (New): The method as in claim 13, wherein said liquid crystal display device is a reflective type liquid crystal display device or a transflective type of liquid crystal display device.